

Substitute Form PTO-1449 (Modified)  <b>Information Disclosure Statement</b> by Applicant (Use several sheets if necessary)  (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-213002	Application No. 09/455,991
	Applicant Ohtani, et al.		
	Filing Date December 6, 1999	Group Art Unit 2815	

### U.S. Patent Documents


Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
<i>Q</i>	AA	6 365 933	Apr 2, 2002	Yamazaki et al.			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

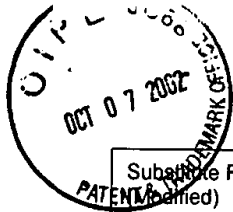
### Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

### Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
<i>Q</i>	AQ	O. Schoenfeld et al., "Crystallization of amorphous silicon by NiSi <sub>2</sub> precipitates." Thin Solid Films 261 (1995) 236-240.
	AR	
	AS	
	AT	

Examiner Signature 	Date Considered 1/23/02
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	



Substitute Form PTO-1449 (Patent Examined)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-213002	Application No. 09/455,991
<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary)  (37 CFR §1.98(b))		Applicant Ohtani, et al.	
		Filing Date December 6, 1999	Group Art Unit 2815

**U.S. Patent Documents**

Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	5 569 936	Oct 29, 1996	Zhang et al.			
	AB	5 591 987	Jan 7, 1997	Yamazaki et al.			
	AC	5 608 232	Mar 4, 1997	Yamazaki et al.			
	AD	5 614 732	Mar 25, 1997	Yamazaki			
	AE	5 627 384	May 6, 1997	Teramoto et al.			
	AF	5 639 698	Jun 17, 1997	Yamazaki et al.			
	AG	5 646 424	Jul 8, 1997	Zhang et al.			
	AH	5 677 549	Oct 14, 1997	Takayama et al.			
	AI	5 696 386	Dec 9, 1997	Yamazaki			
	AJ	5 717 224	Feb 10, 1998	Zhang			
	AK	5 763 899	Jun 9, 1998	Yamazaki et al.			
	AL	5 814 540	Sep 29, 1998	Takemura et al.			
	AM	5 821 138	Oct 13, 1998	Yamazaki et al.			
	AN	5 821 563	Oct 13, 1998	Yamazaki et al.			
	AO	5 869 363	Feb 9, 1999	Yamazaki et al.			
	AP	5 888 858	Mar 30, 1999	Yamazaki et al.			
	AQ	5 897 374	Apr 27, 1999	Lin			
	AR	6 207 969	Mar 27, 2001	Yamazaki			

**Foreign Patent Documents or Published Foreign Patent Applications**

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AS							
	AT							
	AU							
	AV							
	AW							

Examiner Signature 	Date Considered 11/23/02
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	